

Date: December 10, 2001

Page 1 of 3

FORM PTO-1449 (Coll.)

ATTN: DOCKET NO.

SERIAL NUMBER

1-0133966-8

09,829,435

LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANT'S INFORMATION
STATEMENT

APPLICANT

Yoel ARIELI, et al.

FILING DATE

April 9, 2001

GROUP PART UNIT

2877

U.S. PATENT DOCUMENTS

Examiner's Initials	DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
Sub ↓	AA	5,969,855	Oct. 1999	Ishiwata, et al.	359	386
	AB	5,969,853	Oct. 1999	Takaoka	359	370
	AC	5,936,253	Aug. 1999	Sugawa	250	548
	AD	5,870,191	Feb. 1999	Shirley, et al.	343	356
	AE	5,814,815	Sep. 1998	Matsumoto, et al.	250	311
	AF	5,751,475	May 1998	Ishiwata, et al.	359	387
	AG	5,619,372	Apr. 1997	Hellmuth, et al.	359	289
	AH	5,600,440	Feb. 1997	Bendall	356	345

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRAN- SLATION
Sub ↓	AI	JP 9230247	9/1997	Japan		
	AJ	JP 9179620	7/1997	Japan		
	AK	JP 8094936	4/1996	Japan		

OTHER ARTS (Name, Author, Title, Date, and Page)

Sub ↓	AI	Phillion DW "General Methods for Generating Phase-Shifting Interferometry Algorithms" Applied Optics Vol. 36, 8098, (1997)
	AJI	Philia M "Stray-Light Problem in Phase Contrast Microscopy or Toward Highly Sensitive Phase Contrast Devices: A review" Optical Engineering Vol. 32, 1199 (1993)

EXAMINER'S SIGNATURE

DATE CONSIDERED

11/6/01

EXAMINER

Initial reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date December 4, 2001

Page 3 of 3

FORM PTO-4449 (CGIB)

UTILITY DOCKET NO.

SERIAL NUMBER

443396-8

09 829 435

LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANT'S INFORMATION
STATEMENT

APPLICANT

Yocet ARTHUR et al

FILING DATE

April 9, 2001

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2877

U.S. PATENT DOCUMENTS

Examiner's Initials	DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
AL	AA	5,159,474	Oct 1992	Franko, et al	359	29
	AB	5,777,736	Jul 1998	Horton	356	346
	AC	4,653,921	Mar 1987	Kwon	256	353
	AD					
	AE					

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
AM	EP 0 585 099	8/1993	Europe			
AN	GB 2,315,700	2/1998	Great Britain			
AO						

OTHER ART (including Author, B6's, Patents, Priors, etc.)

AP	AI	Golden J. J. Zernike Test I Analytical Aspects	Applied Optics, Vol. 16, 205 (1977)
AR	AJ	Bruning J.H. et al. Digital Wavefront Measuring Interferometry for Testing Optical Surfaces and Lenses	Applied Optics, Vol. 13, 2693 (1974)
	AK		
	AL		

EXAMINER

DATE CONSIDERED

11/16/03

EXAMINER

Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Page 2 of 3

FORM PTO-1449 (Colb.)

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1-013596-8

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LIST OF PATENTS AND PUBLICATIONS
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Yocum et al.

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2877

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Examiner's Initials	DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
sk	AA	5,471,303	Nov. 1995	Ar et al.	356	357
	AB	5,446,540	Aug. 1995	Lin	356	345
	AC	5,235,587	Apr. 1993	Bearden, et al.	369	105
	AD	4,407,569	Oct. 1983	Piller, et al.	350	509
	AE	4,199,366	Feb. 1980	Doyle	356	346

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DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANSLATION
AI	JP 7261089	10/1995	Japan		
AG	JP 7335341	8/1995	Japan		
AH	JP 6186504	7/1994	Japan		

OTHER ART (include Author, Title, Periodic Pages, etc.)

AI	Soda I. and Kawata S. "Separation of Phase and Absorption Images in Phase-contrast Microscopy" Journal of the Optical Society of America A, Vol. 9, 924 (1992)
AK	Creath K. "Phase Measurement Interferometry Techniques" Progress in Optics, XXXI, 348 (1988)
AL	Grewenkamp J. "Generalized Data Reduction for Heterodyne Interferometry" Optical Engineering, Vol. 23, 35 (1984)
AM	Morgan C. J. "1-D Fast Squares Estimation in Phase-Measurement Interferometry" Optics Letters, Vol. 7, 508 (1982)

EXAMINER

DATE CONSIDERED

4/16/03

EXAMINER

Initial reference considered, whether or not citation is in conformance with MPEP 2001. Draw filing through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.